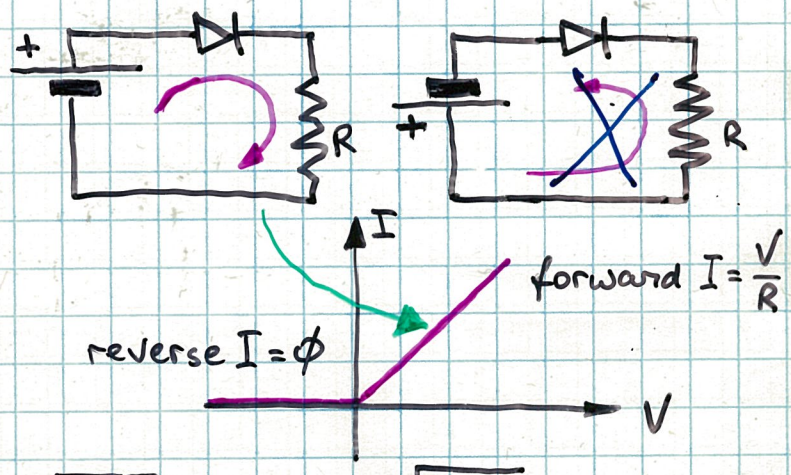
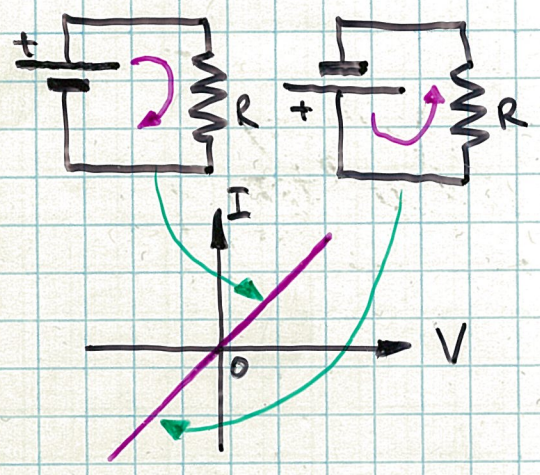
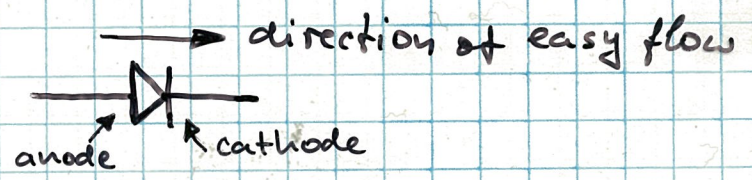


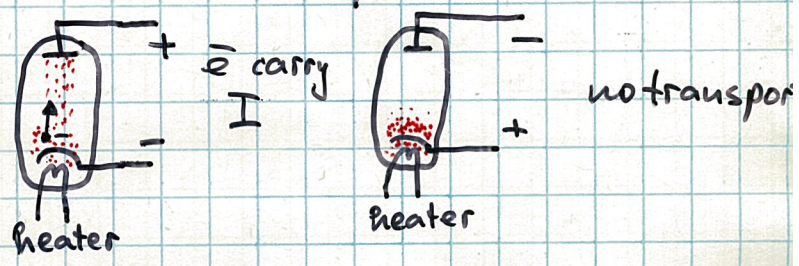
# Non-linear circuit elements

DH. Ch. 5

## Ideal diodes

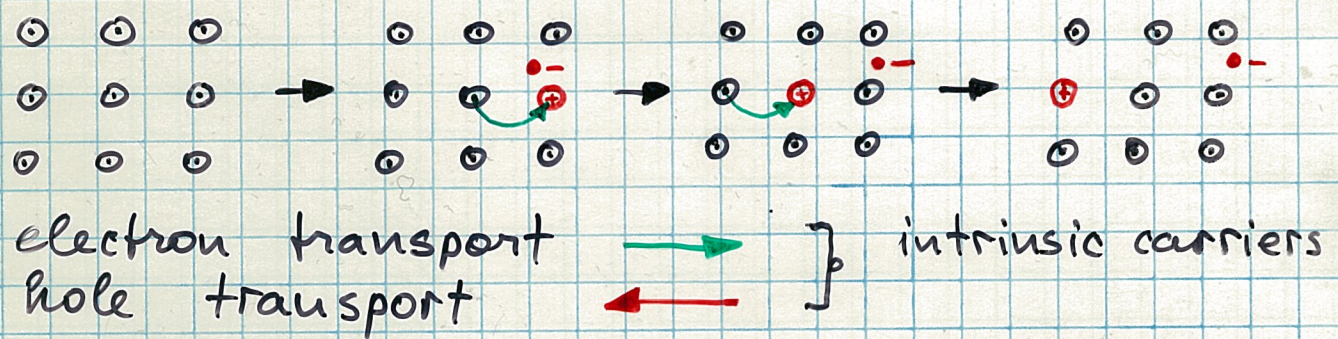


E.g. vacuum diodes



## Semiconductor diodes

- pure semiconductors (Si, Ge)



pure semiconductor:  $N_{\text{holes}} = N_{\bar{e}} \Rightarrow \frac{1}{2}$  current is carried by  $\bar{e}$ ,  $\frac{1}{2}$  by holes.

- recombination is a function of temp. From stat mech: conductivity  $\propto$  density of charges  $\propto \exp(aT)$  !



• doped semiconductors : add impurities

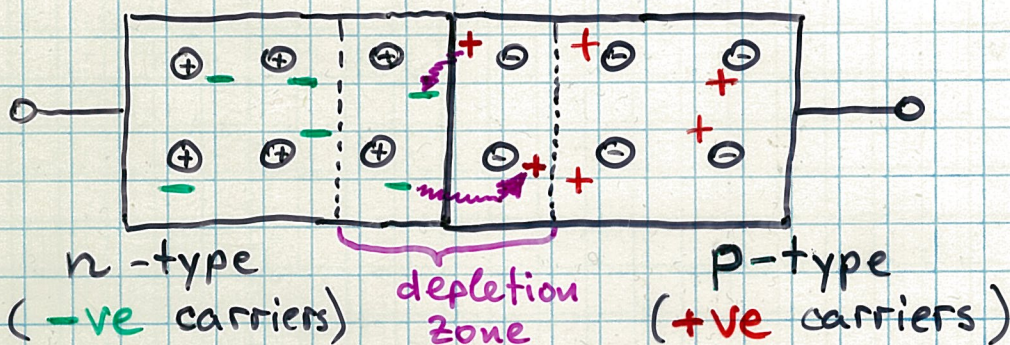
impurity =  $(3+)$  = hole  $\Rightarrow$  majority carrier is a hole (positive)  $\Rightarrow$  p-type  
(e.g. B; acceptor)

impurity =  $(5+)$  =  $\bar{e}$   $\Rightarrow$  majority carrier is  $\bar{e}$  (-ve)  $\Rightarrow$  n-type  
(e.g. P; donor)

At room temperature, about 1 in  $10^{12}$  atoms in pure semiconductor is thermally excited into an electron-hole pair. In doped semiconductors, extrinsic carriers can have concentration of several ppm  $\rightarrow$  1,000,000 times higher!

N.B. doping can be controlled.

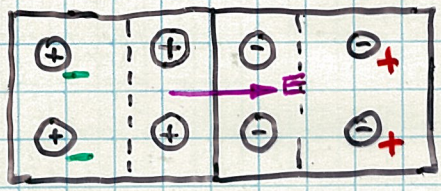
• pn junction



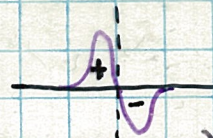
near the contact region, there is a tendency for excess carriers in one region to **diffuse** into the other region, and to **recombine**, leaving lower than usual concentration of free carriers near the junction - a depletion zone

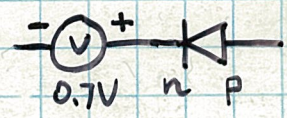


Depletion produces a dipole field across the junction, i.e. a barrier voltage

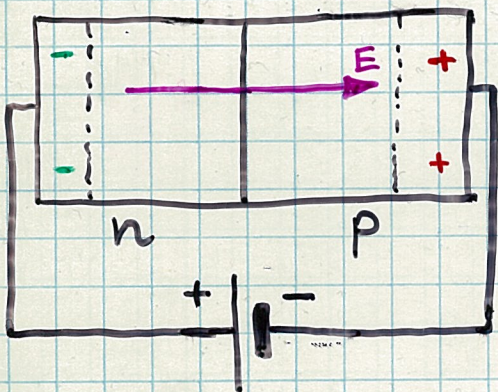


$n \quad \uparrow \quad p$   
 $\Delta V \equiv$  contact potential

$E =$  electric dipole field   
 $\Delta V \approx 0.7V$  (Si, room temperature)

i.e. real Si diode = 

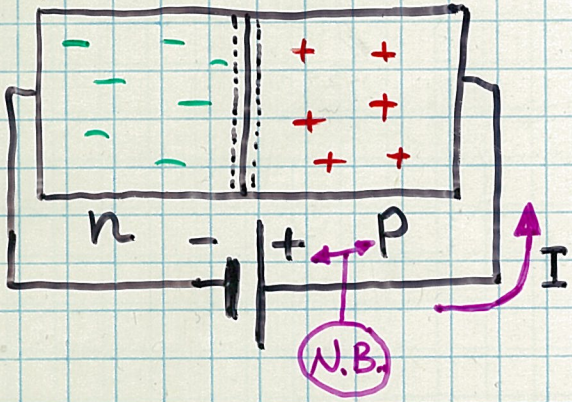
reverse biased



- depletion layer is widened
- no carriers in the depletion region  $\Rightarrow$  no current.

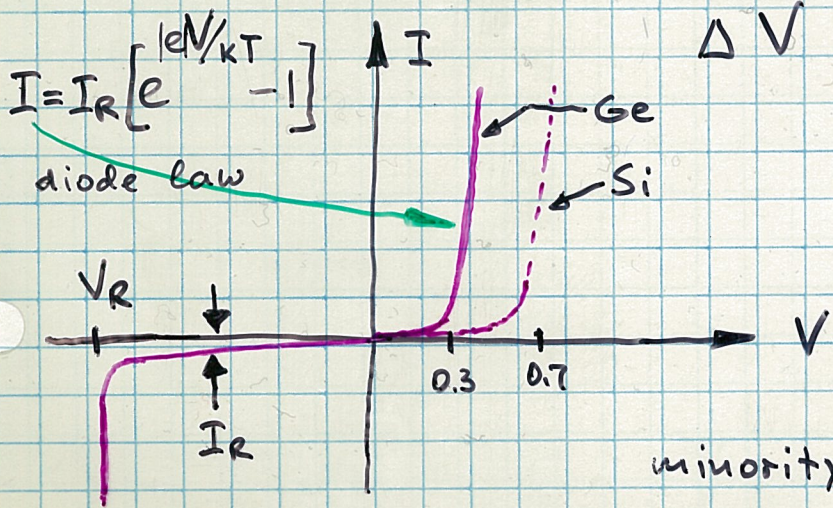
$I \approx \emptyset$  through the junction

forward biased



- external E field overcomes the dipole field & forces the charges into the depletion layer

- no separation of charges,  $\Delta V \approx \emptyset$  across the junction.

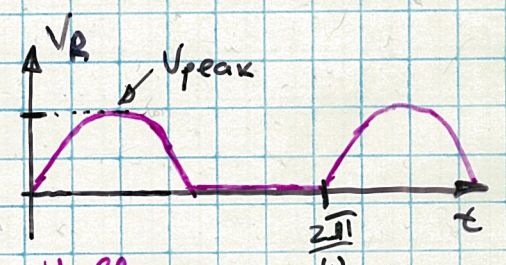
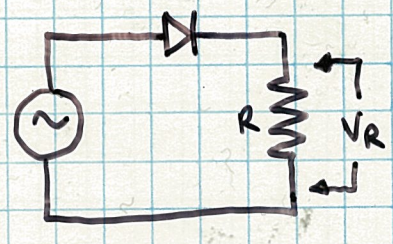
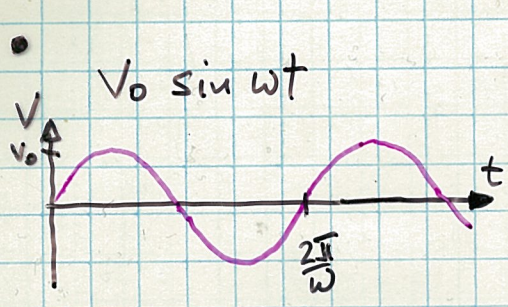


$V_R =$  reverse breakdown voltage

$I_R =$  reverse leakage current,  $\sim 0.01 \mu A$  for Si  
 minority carriers!



# Rectifier circuits (using diodes)

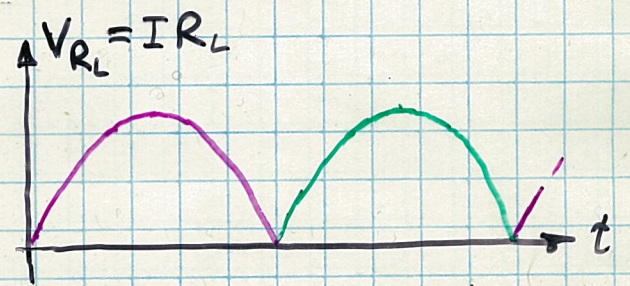
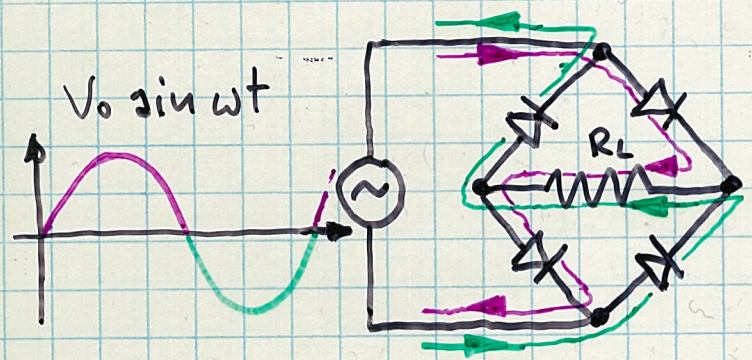


Half-wave rectifier

For a silicone diode,  $V_{peak} = V_o - 0.7V$ , and the voltage is present for  $\approx \frac{1}{2}$  cycle. Ideal diode:  $V_{peak} = V_o$

Average (DC) voltage: 
$$\overline{V_{DC}} = \frac{V_o}{T} \int_0^{T/2} \sin \omega t dt = \frac{V_o}{\pi}$$

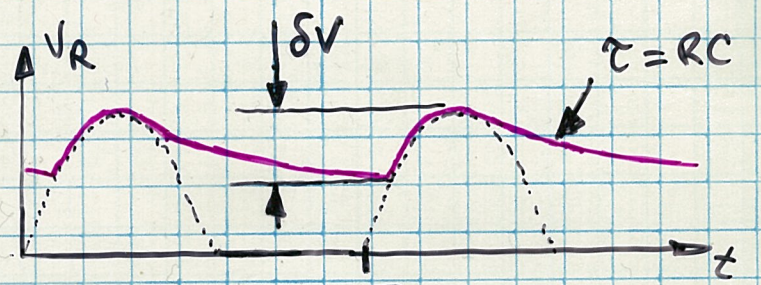
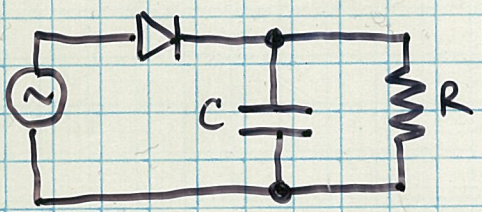
- Half-wave rectification:  $\frac{1}{2}$  the time, no current
- Full-wave rectification: can do better by clever switching of the paths!



Full-wave rectifier

Here 
$$\overline{V_{DC}} = \frac{V_o}{T} \int_0^T |\sin \omega t| dt = \frac{2V_o}{\pi}$$

- AC  $\rightarrow$  DC conversion: need a low-pass filter



Real output: DC + "ripple"  

$$\overline{V_{DC}} + \Delta V$$
 shown for  $\omega RC \gg 1$



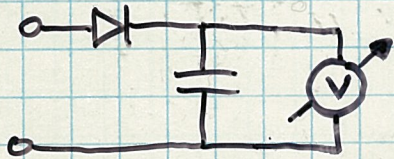
Peak-to-peak ripple voltage is

$$\Delta V \approx V_0 (1 - e^{-T/RC}) \approx \frac{2\pi V_0}{\omega RC}$$

Bridge rectifier  
(full-wave)  
reduces this by  $\frac{1}{2}$

$$\Rightarrow \frac{\Delta V}{V_{DC}} \propto \frac{T}{RC} = \frac{T}{\tau}$$

• AC meters




peak-reading AC voltmeter

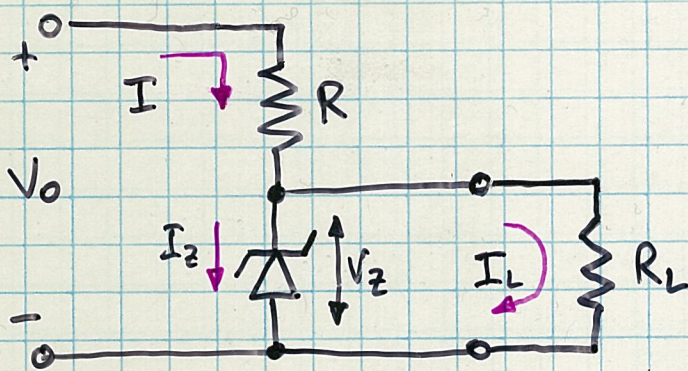
Sinusoidal input  $\rightarrow V_0 = \sqrt{2} V_{rms}$

- need corrections for non-ideal diodes
- readings not valid for non-sinusoidal input voltages; use with caution

Voltage references

 (using diodes II)

Zener diodes operate in reverse-breakdown mode to take advantage of the well-defined voltage at which it occurs for every given diode.



Voltage across Zener diode = const. (rating)

$$\left. \begin{aligned} I_L &= \frac{V_Z}{R_L} \\ I &= \frac{V_0 - V_Z}{R} \end{aligned} \right\} I_Z = I - I_L$$

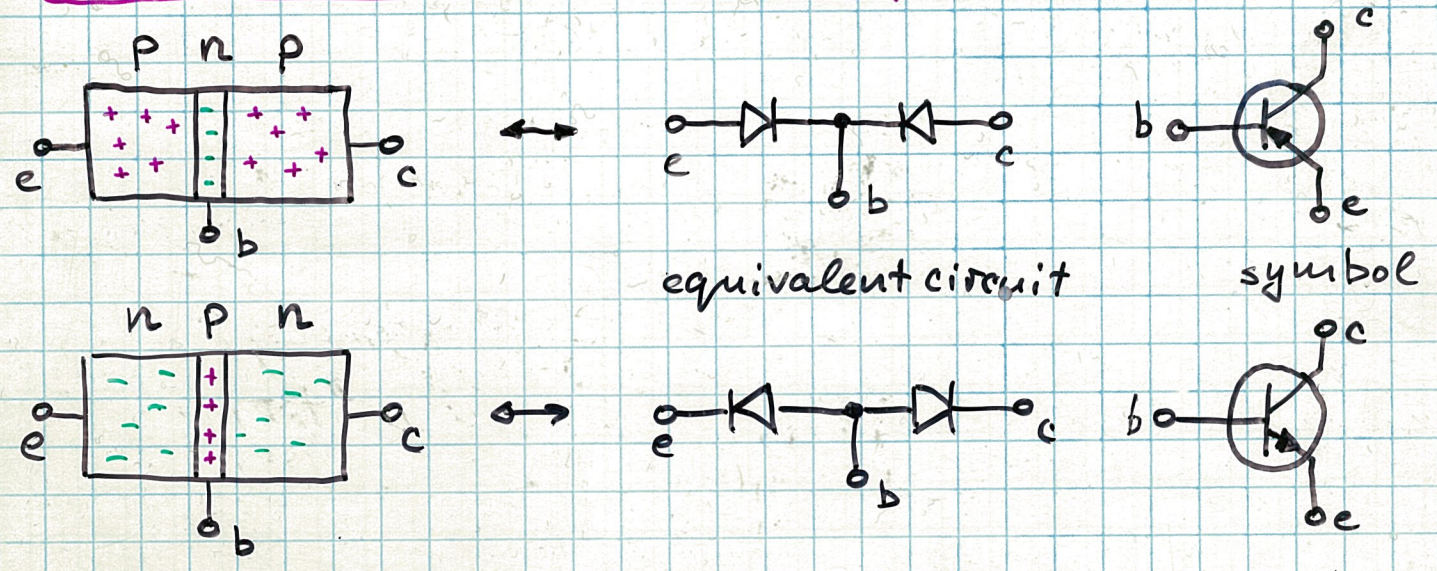
as long as  $I_Z <$  operating limit of diode

NB: in normal operation, the cathode of a Zener diode is +ve.

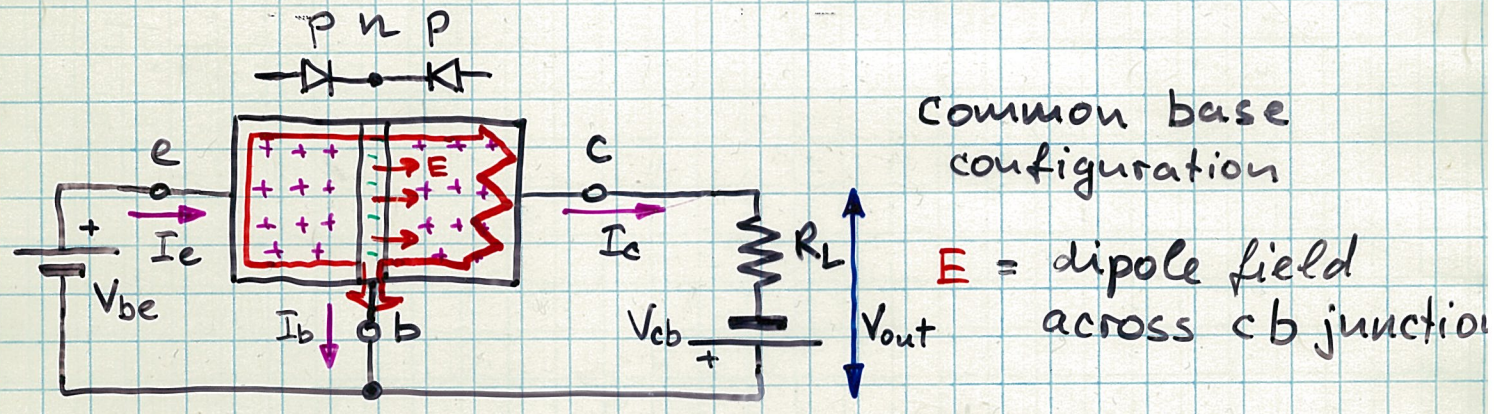


# Transistors: an introduction

DH Ch.8



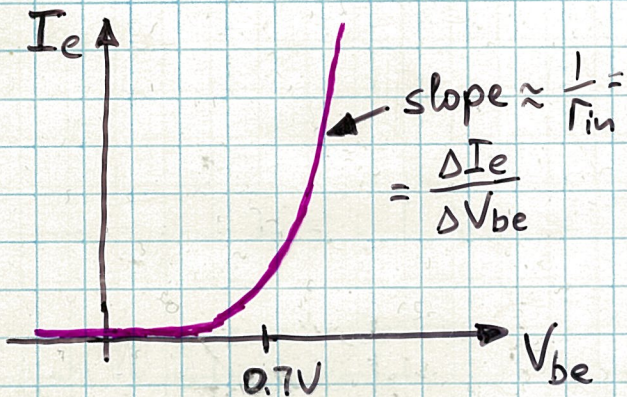
Middle layer: very thin  
 3 electrodes: base, emitter, collector  
 conduction by both  $e^-$  and  $h^+$   $\rightarrow$  bipolar transistors



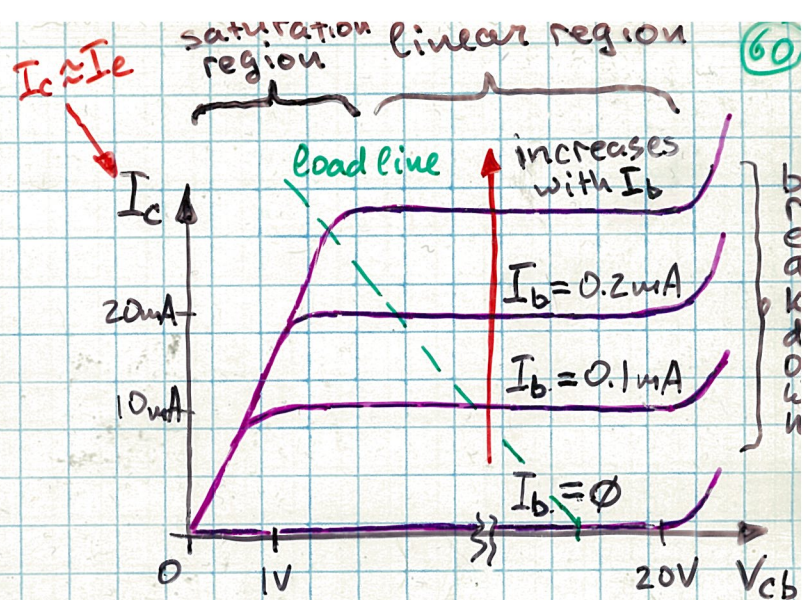
- eb junction is biased forward  $\Rightarrow$  holes are injected into base region.
- cb junction is reverse biased  $\Rightarrow$  exists a dipole field across cb junction s.t. the holes injected into the base are swept into the collector. Because of the geometry, most holes end up in the collector  $\Rightarrow I_c \lesssim I_e$
- if  $V_{be}$  is reversed, the eb junction is reverse biased  $\Rightarrow$  no current flows, since cb junction (also r.b.) does not inject holes into base  $\Rightarrow$  no collector current



• VI characteristics



$r_{in}$  = input impedance  
(of the eb junction)  
typically,  $r_{in} \approx 100 \Omega$



along the load line:

$$V_{out} = V_{cb} - I_c R_L$$

• pnp transistor as an amplifier

① KCL:  $I_e = I_c + I_b$  with  $I_b \ll I_c \approx I_e$

② small changes in  $V_{be} \Rightarrow$  VI characteristic is approx. linear:  $I_e \approx \frac{V_{be}}{r_{in}} [+const]$

③  $V_{out} = V_{cb} - I_c R_L \approx V_{cb} - I_e R_L = V_{cb} - \frac{V_{be}}{r_{in}} R_L$

$$\Rightarrow \Delta V_{out} = \frac{\Delta V_{be}}{r_{in}} R_L$$

$$\Rightarrow \text{Voltage gain} = G_v = \frac{\Delta V_{out}}{\Delta V_{in}} = \frac{\Delta V_{out}}{\Delta V_{be}} = \frac{R_L}{r_{in}}$$

typically,  $r_{in} \approx 100 \Omega$ ,  $R_L \approx 10 k\Omega \Rightarrow G \approx 100$

$\Rightarrow$  small changes in the  $V_{be}$  cause large changes in  $V_{out} \Rightarrow$  amplifier

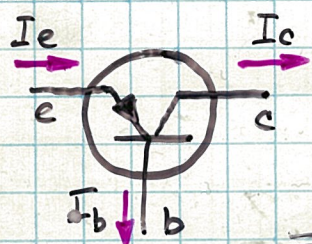
• saturation: rapid buildup of  $I_c$  as excess  $h^+$  are allowed to pass into c.  
linear ("active"): all excess  $h^+$  go into c.



• current gain

$\alpha$  = fraction of  $h^+$  diffusing across narrow  $b$  region

$1-\alpha$  = fraction of  $h^+$  recombining with  $e^-$  in  $b$



$$I_c = \alpha I_e$$

$$I_b = (1-\alpha) I_e$$

$$G_i = \frac{I_c}{I_e} = \alpha$$

$$\beta = \frac{I_c}{I_b} = \frac{\alpha}{1-\alpha}$$

$\Rightarrow G_i$  fairly constant over active region

• once the operating point has been established,

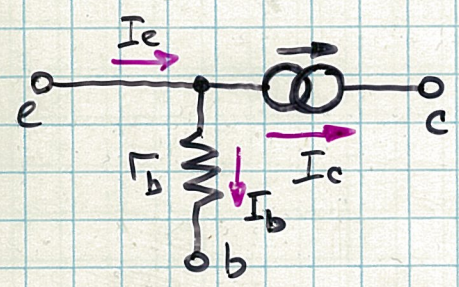
i.e. once different bias voltages have been chosen

(thus fixing  $r_{in}$ , for example), variations due

to small signals can be treated as approx.

linear:

Reduced T model

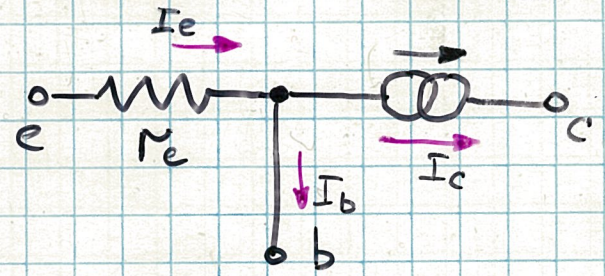


$$I_c = \alpha I_e = \beta I_b$$

$$G_v = \frac{V_{out}}{V_{in}} = \frac{I_c R_L}{I_b r_b} = \frac{\beta R_L}{r_b} = \frac{R_L}{r_{in}}$$

$$\Rightarrow r_{in} = r_b / \beta$$

Ebers-Moll model



$$I_c = I_e \left[ e^{-V_{be}/V_T} - 1 \right]$$

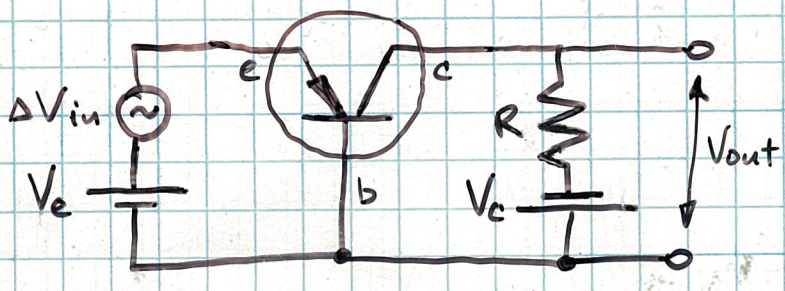
$$V_T = \frac{kT}{q_e} \approx 25 \text{ mV } @ 20^\circ\text{C}$$

$$r_{in} = r_e = \frac{V_T}{I_c} = \frac{25 \cdot 10^{-3}}{I_c} \Omega$$

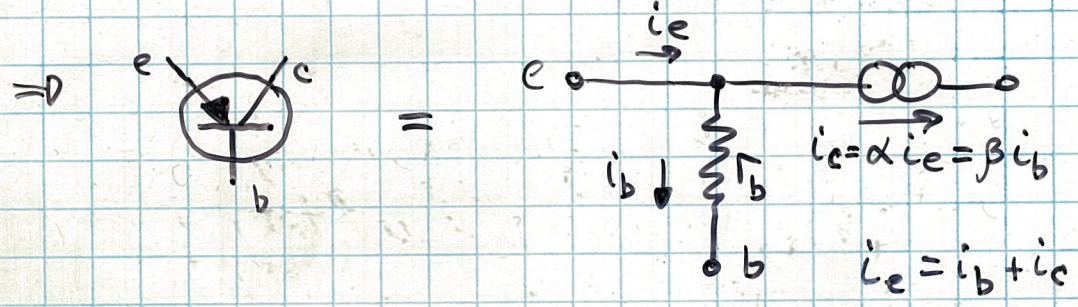
• model's parameters vary when the operating point is changed; need to look them up in data tables.



# Ex. Common-base amplifier



typical values  
 $R = 10,000 \Omega$   
 $r_b = 800 \Omega$   
 $\beta = 100$



with  $i_e, i_b, i_c$  indicating the small signal currents

$$\Rightarrow \Delta V_{in} = i_b r_b \qquad \beta = \frac{\alpha}{1-\alpha} \Leftrightarrow \alpha = \frac{\beta}{1+\beta}$$

$$\Delta V_{out} = i_c R = \alpha i_e R = \beta i_b R$$

$$\Rightarrow G_v = \frac{\Delta V_{out}}{\Delta V_{in}} = \frac{\beta i_b R}{i_b r_b} = \beta \frac{R}{r_b} = \frac{1}{8} \cdot 10^4 = 1250$$

$$G_i = \frac{i_{out}}{i_{in}} = \frac{i_c}{i_e} = \alpha = \frac{\beta}{1+\beta} \approx 0.99$$

Power gain  $G_p = G_v G_i \approx 1238$

$$r_{in} = \frac{r_b}{\beta} = 8 \Omega$$

$$r_{out} = R = 10,000 \Omega$$

low } impedance  
 high } transformer  
 8:10,000

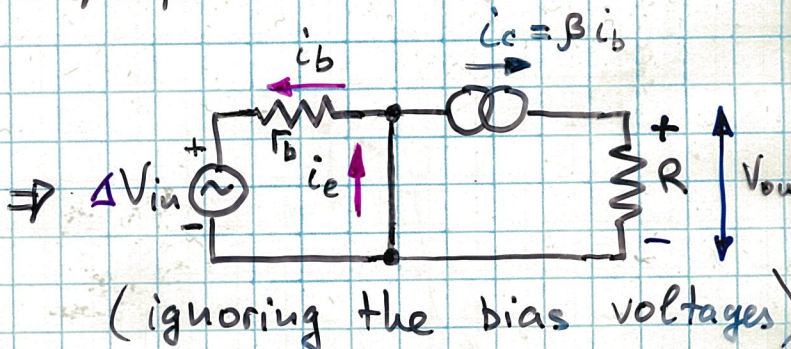
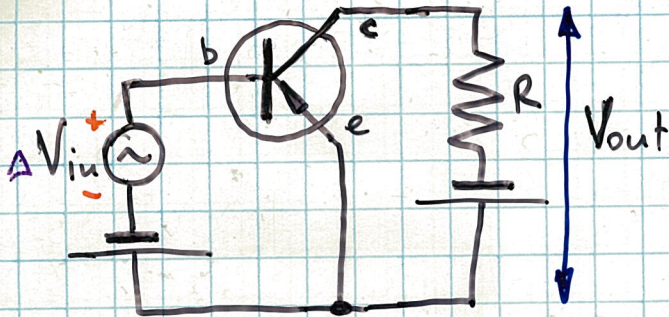
Note:  $G > 0 \Rightarrow$  non-inverting amplifier

The same transistor can be connected in a different manner, e.g. common-emitter configuration. The analysis of this circuit is similar to the common-base configuration.

In brief:



### Ex. Common-emitter amplifier



! Keeping the signs straight!

- since the emitter-base junction is biased forward, a small +ve  $\Delta V_{in}$  will decrease the base current, i.e. cause a -ve  $i_b$

$$\left. \begin{aligned} \Delta V_{in} &= -i_b r_b \\ \Delta V_{out} &= i_c R = \beta i_b R \end{aligned} \right\} G_v = \frac{\beta R}{-r_b} = -\beta \frac{R}{r_b}$$

For the same values as before:

$$\beta = 100 \quad r_b = 100 \Omega \quad R = 10,000 \Omega \quad \Rightarrow G_v = -1250$$

- $G_i = \frac{i_c}{i_b} = \beta = 100$  (was 0.99) ↑  
inverting amp!

- $|G_p| = |G_{vs} G_i| = 125,000$  (was 1238)

- $r_{in} = r_b = 800 \Omega$   
 $r_{out} = R = 10,000 \Omega$  } impedance ratio now 8:100 (was 8:10,000)

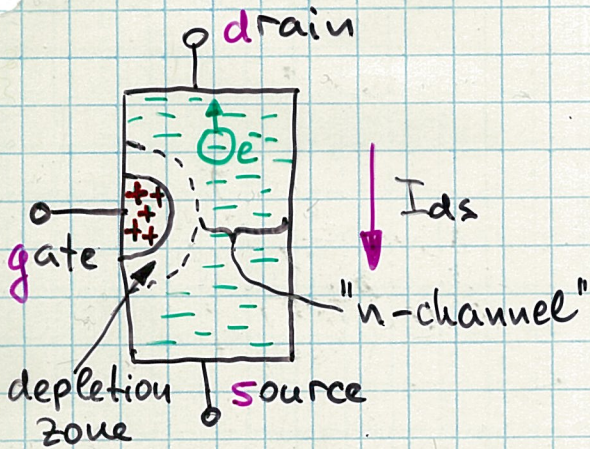
Common-base: modifies impedance,  $G_i \approx 1$

Common-emitter: high  $G_{vs}$  and high  $G_i$

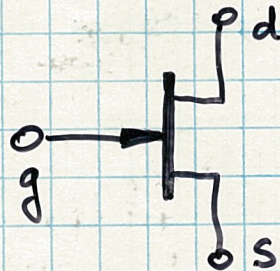


# JFETs

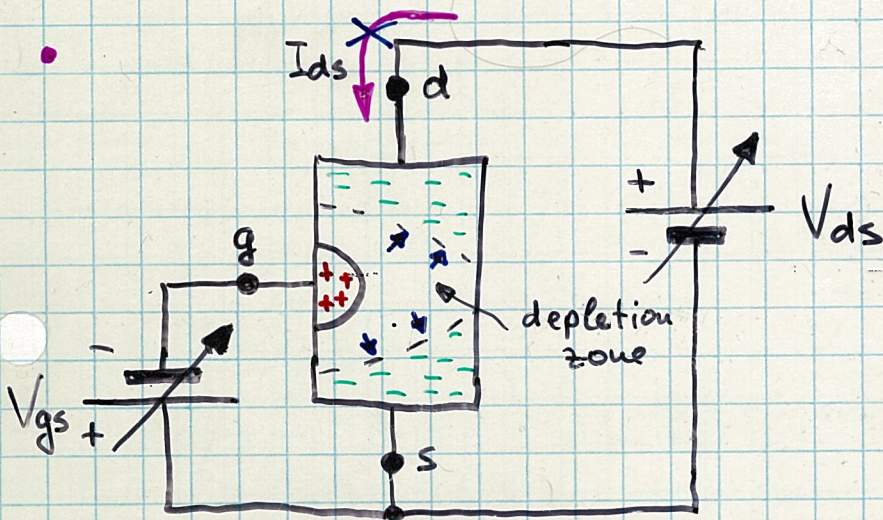
• n-channel Junction Field-Effect Transistor



literally: source and drain of  $e^-$



in practice, d & s are sometimes interchangeable.



① When  $V_{gs} = \phi$  ("grounded gate")  
 $I_{ds}$  flows easily (ON,  $R \sim 25-100 \Omega$ ), limited by the max device dissipation rating,  $I_{ds} V_{ds}$

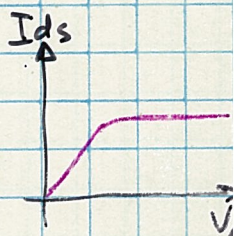
② Increase  $V_{gs}$  as shown  $\Rightarrow$  gate-channel diode is highly reverse-biased  $\Rightarrow$  depletion zone widens all the way across the n-channel  $\Rightarrow$  current  $I_{ds}$  is completely "pinched off" (OFF,  $R \sim 10^9 \Omega$ )

Typical  $V_{gs, OFF} \sim -2$  to  $-15V$  (JFETs used as switches)

•  $I_{ds}$  dependence on  $V_{ds}$

$V_{ds}$  small:  $I_{ds} \propto V_{ds}$  (ohmic region)

$V_{ds}$  large:  $I_{ds}$  saturates (pinch-off region)

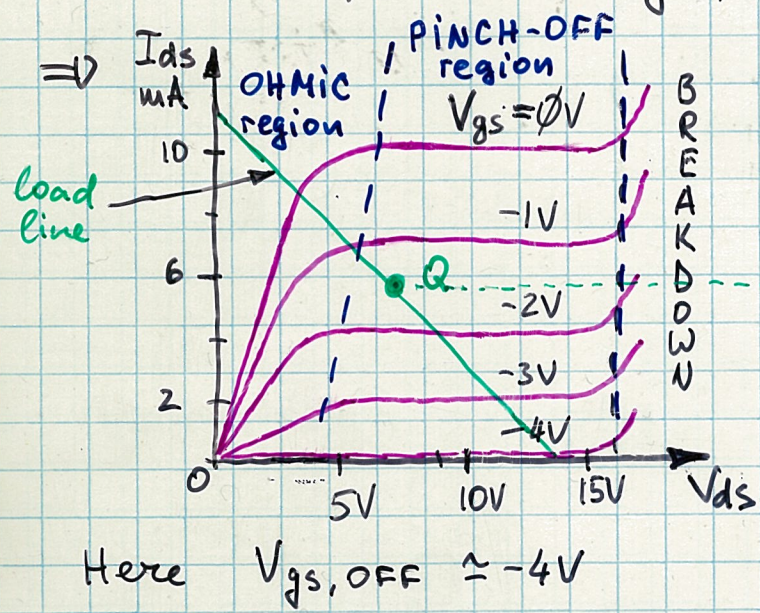




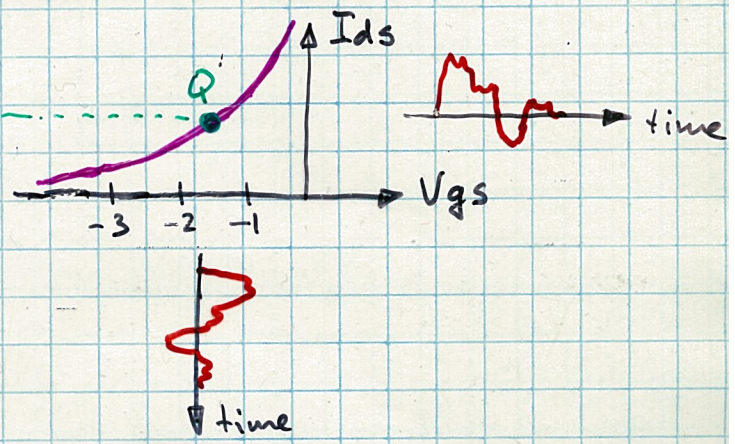
Reason: ohmic (IR) voltage drop across the channel increases with  $I_{ds}$  and pushes the gate potential (already -ve relative to s) even more -ve relative to d  $\Rightarrow$  increasing reverse bias  $\Rightarrow$  pinching  $I_{ds}$  more!

! Negative feedback: two effects cancel  $\Rightarrow$  saturation.

- $I_{ds}$  still depends on  $V_{gs}$ , of course.



Changes in  $V_{gs}$  cause changes in  $I_{ds}$

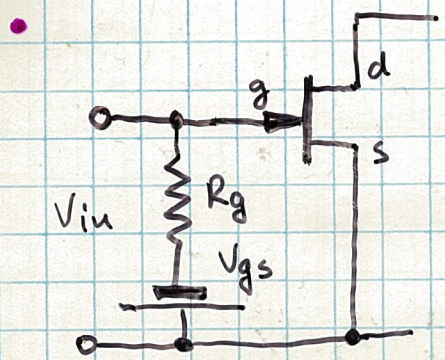


$V_{gs}$  (and  $I_{ds}$ ) have a dc component which is the average value of the input voltage (output current)  $\Rightarrow$  we are working in the regime of small signals (AC) about those time-average values (DC).

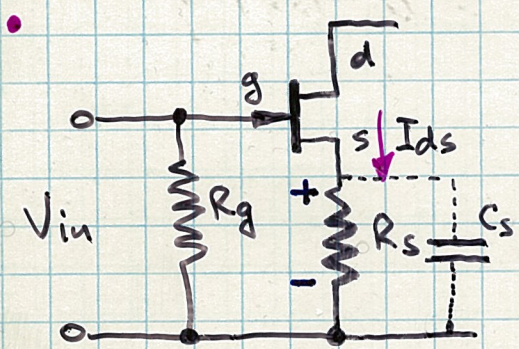
These average (DC) values are known as quiescent voltage and current, or a quiescent operating point Q, about which the signal varies



# Notes on practical JFET circuits



Gate-source leakage current is small (the resistance of a reverse-biased g-s junction is high)  $\Rightarrow$  to control input impedance, add  $R_g \lesssim 10M\Omega$

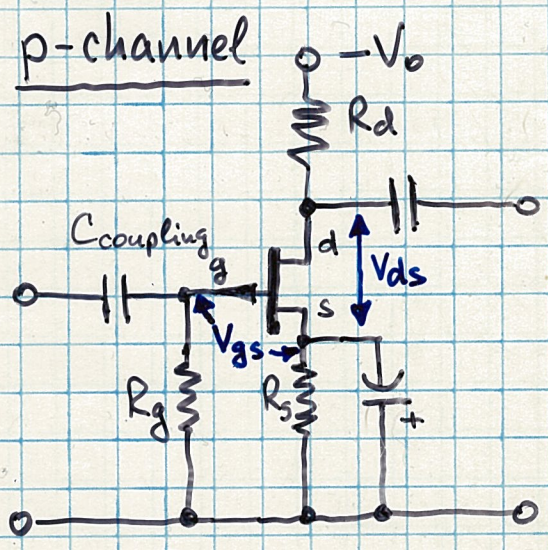
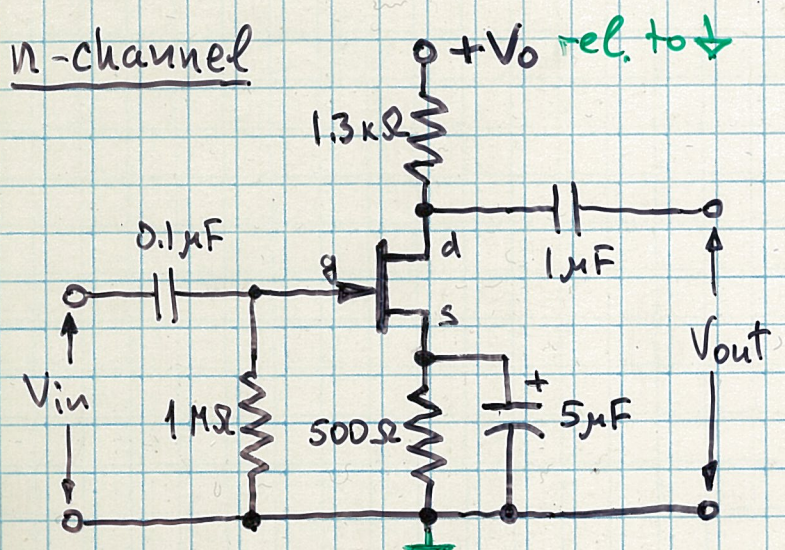


Inconvenient to need a second battery to supply  $V_{gs}$ . Use self-biasing by including a series  $R_s \sim 1k\Omega$ . Voltage drop across  $R_s$  is  $I_{ds}R_s$ , -ve bias of g relative to s

Also: can use a  $C_s$  in parallel to  $R_s$  to smooth out AC variations due to input signals.

- Add capacitors in series at the input and output: DC currents will be "confined" to the FET circuit, and the AC [small] signals will flow freely across C's

## Ex1. Practical circuits



## Ex2. Lab experiment #5